

HIGH SPEED ENVELOPE DETECTOR AND METHOD

This invention pertains generally to electrical signal processing circuits and, more particularly, to an envelope detector and method for determining when a differential signal is greater than a predetermined level.

As illustrated in Figure 1, the differential signal DPIN - DNIN is a cyclical switching signal in which DPIN and DNIN alternate in level during successive cycles and cross over during a switching interval 11 between the cycles. During each cycle, there is a stable period 12 in which both DPIN and DNIN remain constant in level. The differential signal is considered to be valid when it is greater in level than a reference signal V_{REF} , i.e. when $|DPIN - DNIN| > V_{REF}$, and invalid when it is below the level of the reference signal, i.e. when $|DPIN - DNIN| < V_{REF}$.

In a typical application, the differential signal might, for example, have a level of about 150--180 mV, and the reference voltage might have a level on the order of 125 mV. The differential signal is a high speed signal, with a typical rate of on the order of 0.5 gigabit per second and a relatively wide common mode voltage V_{COM} ranging from about -50 mV to about +500 mV. The reference voltage and the common mode voltage are both referenced to ground. For the envelope detector to begin indicating the validity of the differential signal within a few cycles of start-up, it must complete its evaluation and indicate the validity of the signal within about 8 nanoseconds, or less. In this particular example, the differential signal is considered to be valid if $DPIN - DNIN > V_{REF}$ or $DNIN - DPIN > V_{REF}$ for about 0.5 nanosecond or more during the stable period.

Differential signals of this type are commonly found in and around personal computers, e.g. on USB keyboard cables.

Envelope detectors heretofore provided have had certain limitations and disadvantages such as only working with single-ended signals, relatively high
5 signal levels (e.g., 0.7 volt), and relatively slow signals (e.g., 10 Mhz or less).

It is in general an object of the invention to provide a new and improved envelope detector and method.

Another object of the invention is to provide an envelope detector and method of the above character which are suitable for use with differential
10 signals.

Another object of the invention is to provide an envelope detector and method of the above character which operate at a higher speed than envelope detectors of the prior art.

These and other objects are achieved in accordance with the invention by
15 providing an envelope detector and method for determining whether the level of a differential input signal $DPIN - DNIN$ is above a reference voltage V_{REF} . The differential input signal is converted to a differential current $IDP - IDN$, the reference voltage is converted to a reference current I_{REF} , the currents are compared to determine if $|IDP - IDN|$ is greater than I_{REF} , and a valid
20 differential signal is indicated when $|IDP - IDN|$ is greater than I_{REF} .

Figure 1 is a waveform diagram illustrating a differential signal of the type which is monitored for validity by the invention.

Figure 2 is a block diagram of one embodiment of an envelope detector incorporating the invention.

Figure 3 is a simplified circuit diagram of one embodiment of a voltage-to-current converter for use in the embodiment of Figure 2.

Figure 4 is a simplified circuit diagram of one embodiment of a current comparator for use in the embodiment of Figure 2.

- 5 Figure 5 is a block diagram of one embodiment of an output detector for use in the embodiment of Figure 2.

Figure 6 is a waveform diagram, illustrating the operation of the envelope detector.

10 As illustrated in Figure 2, the envelope detector includes a voltage-to-current converter stage 16 which converts the differential input voltage $DPIN - DNIN$ to a differential current $IDP - IDN$ and the reference voltage V_{REF} to a reference current I_{REF} , a comparator stage 17 which determines whether the differential current level is greater than the reference current, a voltage amplifier 18 for increasing the level of the signals from the comparator stage, and an output detector 19 which provides an output signal indicative of a valid differential input signal when the level of the differential current is greater than the reference current. The output detector also maintains the output signal during the switching interval following a cycle in which the level of the differential current is greater than the reference current.

20 In the converter stage, differential input signals $DPIN$ and $DNIN$ are applied to the A and AN inputs of a first voltage-to-current converter 21, and the differential currents IDP and IDN are produced at the Z and ZN outputs of the converter. The reference voltage is applied differentially to a second voltage-to-current converter 22 by applying the reference voltage V_{REF} to the A input of the converter and connecting the AN input to ground. The reference current $I_{REF} - I_{GND}$ appears at the Z and ZN outputs of converter 22. In the embodiment disclosed, V_{GND} and I_{GND} are assumed to be zero, and

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the reference voltage and reference current are referred to simply as V_{REF} and I_{REF} , respectively. However, it will be understood that I_{REF} is actually a differential current which may contain a non-zero ground component.

As illustrated in Figure 3, each of the voltage-to-current converters comprises
5 a current source 24, a differential pair consisting of complementary transistors 26, 27, and current mirroring transistors 28, 29. The current source provides a current I which is divided between transistors 26, 27. The differential voltage is applied to input terminals A, AN which are connected to the bases of transistors 26, 27 to control the differential currents I_A , I_{AN}
10 that are delivered to the current mirroring transistors.

In converter 21, the differential voltages which are applied to terminals A and AN are DPIN and DNIN, and the currents I_A and I_{AN} are IDP and IDN, respectively. The greater the difference in voltage in DPIN and DNIN, the greater the difference in current in IDP and IDN.

15 In converter 22, the reference voltage V_{REF} is applied to input terminal A, input terminal AN is connected to ground, and current I_A is replaced by I_B which is the reference current I_{REF} . Current I_{AN} is replaced by I_{BN} .

Comparator stage 17 includes a first current comparator 31 which compares
20 IDP - IDN with reference current I_{REF} , and a second current comparator 32 which compares IDN - IDP with I_{REF} . Thus, IDP is applied to the A input of comparator 31, IDN is applied to the AN input, I_{REF} is applied to the B input, and I_{GND} is applied to the BN input. In comparator 32, the connections are reversed, with IDN being applied to the A input and IDP being applied to the AN input. I_{REF} is still applied to the B input, and I_{GND} is applied to the BN
25 input.

As illustrated in Figure 4, in each of the comparators, the input terminals A, AN are connected to the bases of transistors 33, 34. These transistors form

current mirrors with transistors 28, 29 in voltage-to-current converter 21, whereby differential currents I_A , I_{AN} (i.e., I_{DP} and I_{DN}) are mirrored from the converter to the comparator. Input terminals B, BN are connected to the bases of transistors 36, 37. These transistors form current mirrors with transistors 28, 29 in voltage-to-current converter 22, whereby the differential currents I_B , I_{BN} (i.e., I_{REF}) are mirrored from the converter to the comparator.

The drains of transistors 33, 36 are connected together and supplied with a current I_C which is divided between I_A and I_B so that $I_C = I_A + I_B$. Similarly, the drains of transistors 34, 37 are connected together and supplied with a current I_{CN} which is divided between I_{AN} and I_{BN} so that $I_{CN} = I_{AN} + I_{BN}$. A current mirror consisting of transistors 38, 39 translates I_C to I_D , and a multiplying current mirror consisting of transistors 41, 42 translates $2I_{CN}$ to I_{DN} . A multiplying current mirror consisting of transistors 43, 44 translates $2I_D$ to I_E . I_{DN} divides between I_E and output terminal Z. Thus, when $I_{DN} > I_E$, current flows out of the output terminal, and when $I_{DN} < I_E$, current flows into the output terminal.

A multiplying current mirror consisting of transistors 38, 46 translates $2I_C$ to I_F , and a current mirror consisting of transistors 41, 47 translates I_{CN} to I_G . A multiplying current mirror consisting of transistors 48, 49 translates $2I_G$ to I_H . I_F divides between I_H and output terminal ZN. Thus, when $I_F > I_H$, current flows out of the output terminal, and when $I_F < I_H$, current flows into the output terminal.

Thus, the voltage at output terminal Z is high if $I_{DN} > I_E$ or if $I_{AN} + I_{BN} > I_A + I_B$, and is low if $I_{DN} < I_E$ or if $I_{AN} + I_{BN} < I_A + I_B$. Similarly, the voltage at output terminal ZN is high if $I_F > I_H$ or if $I_{AN} + I_{BN} < I_A + I_B$, and is low if $I_F < I_H$ or if $I_{AN} + I_{BN} > I_A + I_B$. In other words, the differential voltages at A and AN are results of $(I_A + I_B) - (I_{AN} + I_{BN})$.

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[illegible]



The output of the Schmitt trigger is connected to a driver stage 66 which provides an output signal which is low for valid differential input signals ($|DPIN - DNIN| > V_{REF}$) and high for invalid signals ($|DPIN - DNIN| < V_{REF}$).

- 5 Operation and use of the envelope detector, and therein the method of the invention can be described with reference to the waveforms shown in Figure 6. The differential signal $DPIN - DNIN$ and the reference voltage V_{REF} are converted to a differential current $IDP - IDN$ and a reference current I_{REF} by voltage-to-current converters 21, 22. The level of the differential current is
- 10 compared with that of the reference current in comparators 31, 32, with comparator 31 subtracting I_{REF} from $IDP - IDN$, and comparator 32 subtracting I_{REF} from $IDN - IDP$.

- During cycles in which $DPIN > DNIN$ and the input signal is valid, the voltage V_{67} from the Z output of comparator 31 crosses above the voltage V_{68} from the ZN output of that comparator. When V_{67} is greater than V_{68} , the voltage V_{69} at the output of amplifier 51 is high. During cycles in which $DNIN > DPIN$ and the input signal is valid, the voltage V_{71} from the Z output of comparator 32 crosses above the voltage V_{72} from the ZN output of that comparator. When V_{71} is greater than V_{72} , the voltage V_{73} at the output of
- 15 amplifier 52 is high. During cycles in which the differential input signal is invalid, comparator outputs V_{67} , V_{71} will not cross above outputs V_{68} , V_{72} , and the outputs of amplifiers 51, 52 will remain low.
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- When the output of either or both of amplifiers 51, 52 is high, node 61 is pulled low, and the voltage V_{76} at that node decreases. After a few cycles
- 25 of valid signal, voltage V_{76} will drop to the lower trigger level V_{TL} of Schmitt trigger 63, which then switches to its low (logic 0) output state, thus providing an output signal V_{OUT} at the output of driver stage 66 indicative of a valid differential input signal. The Schmitt trigger remains in its low output state until the node voltage V_{76} rises above the upper trigger level V_{TH} .



5 The difference between the upper and lower threshold voltages of the Schmitt trigger is greater than the glitches 77 in the node voltage which occur during the switching intervals between the cycles of the differential signal. Thus, those glitches will not cause the output state of the Schmitt trigger to change, and they are thereby effectively filtered out.

10 When a valid differential input signal is not present, node voltage V76 is no longer pulled down by the larger 500 μ A current sources, and the 100 μ A current source pulls it in a positive direction. When the node voltage reaches the upper trigger level V_{TH} , the Schmitt trigger switches to its high output state, and it remains in that state until the node voltage drops to the lower trigger level.

15 The invention has number of important features and advantages. It determines the validity of differential input signals of relatively low magnitude and relatively high data rates. Converting the input and reference voltages to currents keeps the d.c. level of operation the same regardless of the common mode voltage of the differential inputs, and it is much easier to do addition and subtraction with currents than with voltages. The effect of glitches arising during the switching interval between successive cycles of the input signal is effectively filtered out.

20 It is apparent from the foregoing that a new and improved envelope detector and method have been provided. While only certain presently preferred embodiments have been described in detail, as will be apparent to those familiar with the art, certain changes and modifications can be made without departing from the scope of the invention as defined by the following claims.